

Notice of References Cited	Application/Control No. 10/550,117		Applicant(s)/Patent Under Reexamination SALMON, NEIL ANTHONY	
	Examiner Christopher P. Rivard		Art Unit 4154	Page 1 of 1

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*	C	US-5,047,783	09-1991	Hugenin, G. Richard	342/179
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	V	Marshall, "Risley Prism Scan Patterns," Proceedings of SPIE (July 1999), Volume 3787, pages 74-86
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.